

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Cline *et al.*

Examiner: Chen, Eric Brice

Serial No.: 10/711,953

Art Unit: 1765

Filed: 10/15/2004

Docket No.: **BUR920040122US1**

Title: **DEEP TRENCH FORMATION IN SEMICONDUCTOR DEVICE FABRICATION**

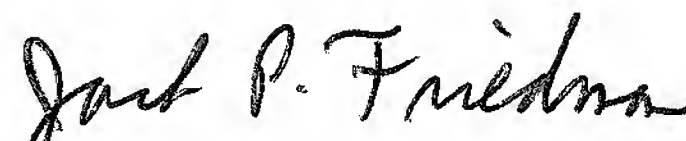
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INTERVIEW SUMMARY

Applicants' representative Khoi D. Nguyen asserts that the Examiner's Interview Summary (Form PTOL-413) mailed on 26 June 2006 accurately describes the substance of the June 20, 2006 telephonic interview between Applicants' representative Khoi D. Nguyen and Examiner Eric B. Chen.

Date: 06/30/2006

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